

Semiconductor devices — Mechanical and climatic test methods —

Part 4: Damp heat, steady state, highly accelerated stress test (HAST)

The European Standard EN 60749-4:2002 has the status of a
British Standard

ICS 31.080.01

National foreword

This British Standard is the official English language version of EN 60749-4:2002. It is identical with IEC 60749-4:2002. It partially supersedes BS EN 60749:1999.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors, which has the responsibility to:

- aid enquirers to understand the text;
- present to the responsible international/European committee any enquiries on the interpretation, or proposals for change, and keep the UK interests informed;
- monitor related international and European developments and promulgate them in the UK.

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Cross-references

The British Standards which implement international or European publications referred to in this document may be found in the *BSI Catalogue* under the section entitled “International Standards Correspondence Index”, or by using the “Search” facility of the *BSI Electronic Catalogue* or of British Standards Online.

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This British Standard, having been prepared under the direction of the Electrotechnical Sector Policy and Strategy Committee, was published under the authority of the Standards Policy and Strategy Committee on 10 September 2002

Summary of pages

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English version

**Semiconductor devices –
Mechanical and climatic test methods
Part 4: Damp heat, steady state, highly accelerated stress test (HAST)
(IEC 60749-4:2002)**

Dispositifs à semiconducteurs –
Méthodes d'essais mécaniques
et climatiques
Partie 4: Essai continu fortement accéléré
de contrainte de chaleur humide (HAST)
(CEI 60749-4:2002)

Halbleiterbauelemente -
Mechanische und klimatische
Prüfverfahren
Teil 4: Feuchte Wärme, konstant, Prüfung
mit hochbeschleunigter Wirkung (HAST)
(IEC 60749-4:2002)

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Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

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CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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Foreword

The text of document 47/1602/FDIS, future edition 1 of IEC 60749-4, prepared by IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60749-4 on 2002-07-02.

This mechanical and climatic test method, as it relates to damp heat, steady state, highly accelerated stress test (HAS), is a complete rewrite of the test contained in clause 4C, chapter 3 of EN 60749:1999.

The following dates were fixed:

- latest date by which the EN has to be implemented
at national level by publication of an identical
national standard or by endorsement (dop) 2003-04-01
- latest date by which the national standards conflicting
with the EN have to be withdrawn (dow) 2005-07-01

Endorsement notice

The text of the International Standard IEC 60749-4:2002 was approved by CENELEC as a European Standard without any modification.
